Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/544,523	LEHRMAN, MIKEL A.	
Examiner	Art Unit	

Nhan T. Tran

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Subclass	Date	Examiner			
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INT	INTERFERENCE SEARCHED					
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Jpdated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, BM_TDB) Text search - see search history printout	8/1/2007	NT